

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination SUGIHARA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 10-168551	06-1998	JP	SHIMAZU ET AL.	(w/ translation)
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	P					
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	D	US-			
	E	US-			
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